Search Notes

Application/Control No.	Applicant(s)/Patent Reexamination	under
10/700,216	SCHANTZ, JOHN	L.
Examiner	Art Unit	
Benny Q. Tieu	2614	

SEARCHED					
Class ·	Subclass	Date	Examiner		
379	229 230 221.08- 221.1	10/28/2006	BQT		
370	401 410 467		•		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING	SEARCH	STRATEGY)
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